

<b>Notice of References Cited</b>	Application/Control No. 09/923,810	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner A. Sefer	Art Unit 2826	Page 1 of 1

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*	B	US-2005/0206825	09-2005	Kaneko et al.	349/141
*	C	US-6,215,077	04-2001	Utsumi et al.	174/268
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**NON-PATENT DOCUMENTS**

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